

Notice of References Cited	Application/Control No. 10/633,500	Applicant(s)/Patent Under Reexamination WU, SHYE-LIN	
	Examiner Lex Malsawma	Art Unit 2823	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,862,244	08-1989	Yamagishi, Hidetaka	257/484
	B	US-5,365,102	11-1994	Mehrotra et al.	257/475
	C	US-5,418,185	05-1995	Todd et al.	438/384
	D	US-6,252,288 B1	06-2001	Chang, Hsueh-Rong	257/471
	E	US-6,399,996 B1	06-2002	Chang et al.	257/484
	F	US-6,404,033 B1	06-2002	Chang et al.	257/484
	G	US-6,426,541 B2	07-2002	Chang et al.	257/472
	H	US-6,448,160 B1	09-2002	Chang et al.	438/527
	I	US-6,656,843 B2	12-2003	Bol, Igor	438/694
	J	US-6,740,951 B2	05-2004	Tsui et al.	257/483
	K	US-6,855,593 B2	02-2005	Andoh et al.	438/237
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Hsu et al., "A Novel Trench Termination Design for 100-V TMBS Diode Application", Nov. 2001, IEEE Electron Device Letters, Vol. 22, No. 11, pp. 551-552.
	V	IBM Technical Disclosure Bulletin, February 1978, pp. 3486-3487.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.